## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier		User Part Number						
Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		PIMC32PAS-Q Part Description						
		MCD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
			TEST					-
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
# A1	<b>PC</b> Preconditioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	464	20960	0		
# A1		MIL-STD-750-1	5 676.65	404	20900	0		
# B1	<b>HTRB</b> High Temperature Reverse Bias	$ \begin{array}{l} \text{M10-3} \text{ ID-750-1} \\ \text{M1039 Method A} \\ \text{Tj} = \text{Tjmax}, \text{ Vr} = 100\% \text{ of max. datasheet} \\ \text{reverse voltage} \end{array} $	1000 hours	415	18680	0		
# A4	<b>TC</b> Temperature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000 cycles	116	5240	0		
# A3 <b>or</b>	<b>UHAST</b> Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %	26.1	116	5240	0		
# A3 alt	<b>AC</b> Autoclave	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)	— 96 hours					
# A2 alt	<b>H3TRB</b> High Humidity High Temperature Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage <sup><math>(1)</math></sup>	1000 hours	116	5240	0		
	<b>IOL</b> Intermittent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta Tj$ = 100 °C for 15000 cycles						
# A5	Internittent Operating Life		1000 hours	116	5240	0		
# C8	<b>RSH</b> Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.		
# C10	<b>SD</b> Solderability	J-STD-002		86	2580	0		

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Small Signal Bipolar Transistor	18680	0	0,23	4,40E+09

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